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BUK7Y18-75B

N-channel TrenchMOS standard level FET

1 March 2013

Product data sheet

1. General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using NXP High-Performance Automotive (HPA) TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

2. Features and benefits

- Q101 compliant
- Suitable for standard level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

3. Applications

- 12 V, 24 V and 42 V loads
- Automotive systems
- DC-to-DC converters
- Engine management
- General purpose power switching
- Motors, lamps and solenoids
- Transmission control

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}$; $T_j \leq 175^\circ\text{C}$		-	-	75	V
I_D	drain current	$V_{GS} = 10\text{ V}$; $T_{mb} = 25^\circ\text{C}$; Fig. 1 ; Fig. 4		-	-	49	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; Fig. 2		-	-	105	W
Static characteristics							
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10\text{ V}$; $I_D = 20\text{ A}$; $T_j = 25^\circ\text{C}$; Fig. 12 ; Fig. 13		-	13.8	18	$\text{m}\Omega$
Dynamic characteristics							
Q_{GD}	gate-drain charge	$I_D = 20\text{ A}$; $V_{DS} = 60\text{ V}$; $V_{GS} = 10\text{ V}$; Fig. 14		-	14.24	-	nC



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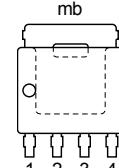
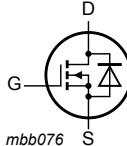
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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Avalanche ruggedness							
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 49 \text{ A}$; $V_{sup} \leq 75 \text{ V}$; $R_{GS} = 50 \Omega$; $V_{GS} = 10 \text{ V}$; $T_{j(init)} = 25 \text{ }^\circ\text{C}$; unclamped		-	-	118	mJ

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source		
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain	 LFPACK56; Power-SO8 (SOT669)	

6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7Y18-75B	LFPACK56; Power-SO8	Plastic single-ended surface-mounted package (LFPACK56; Power-SO8); 4 leads	SOT669

7. Marking

Table 4. Marking codes

Type number	Marking code
BUK7Y18-75B	71875B

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25 \text{ }^\circ\text{C}$; $T_j \leq 175 \text{ }^\circ\text{C}$	-	75	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	75	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$; $V_{GS} = 10 \text{ V}$; Fig. 1 ; Fig. 4	-	49	A

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Symbol	Parameter	Conditions		Min	Max	Unit
		$T_{mb} = 100^\circ\text{C}$; $V_{GS} = 10\text{ V}$; Fig. 1		-	34.9	A
I_{DM}	peak drain current	$T_{mb} = 25^\circ\text{C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; Fig. 4		-	198	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; Fig. 2		-	105	W
T_{stg}	storage temperature			-55	175	°C
T_j	junction temperature			-55	175	°C
Source-drain diode						
I_S	source current	$T_{mb} = 25^\circ\text{C}$		-	49	A
I_{SM}	peak source current	pulsed; $t_p \leq 10\text{ }\mu\text{s}$; $T_{mb} = 25^\circ\text{C}$		-	198	A
Avalanche ruggedness						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 49\text{ A}$; $V_{sup} \leq 75\text{ V}$; $R_{GS} = 50\text{ }\Omega$; $V_{GS} = 10\text{ V}$; $T_{j(init)} = 25^\circ\text{C}$; unclamped		-	118	mJ
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	Fig. 3	[1][2][3]	-	-	J

[1] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[2] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[3] Refer to application note AN10273 for further information.

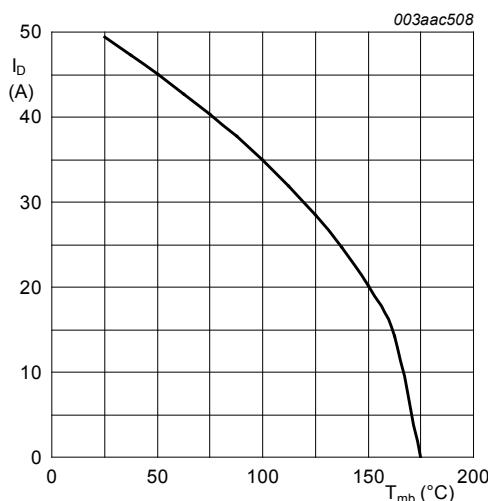


Fig. 1. Continuous drain current as a function of mounting base temperature

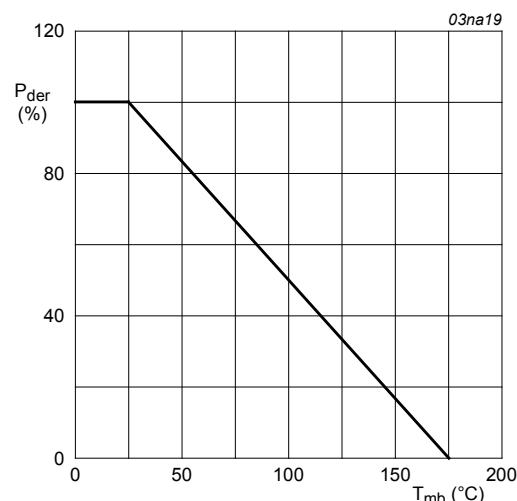


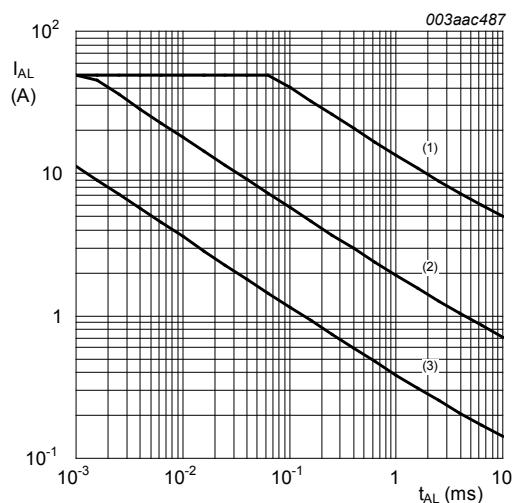
Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot}(25^\circ\text{C})} \times 100\%$$

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(1) Single pulse; $T_j = 25^\circ\text{C}$.

(2) Single pulse; $T_j = 150^\circ\text{C}$.

(3) Repetitive.

Fig. 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

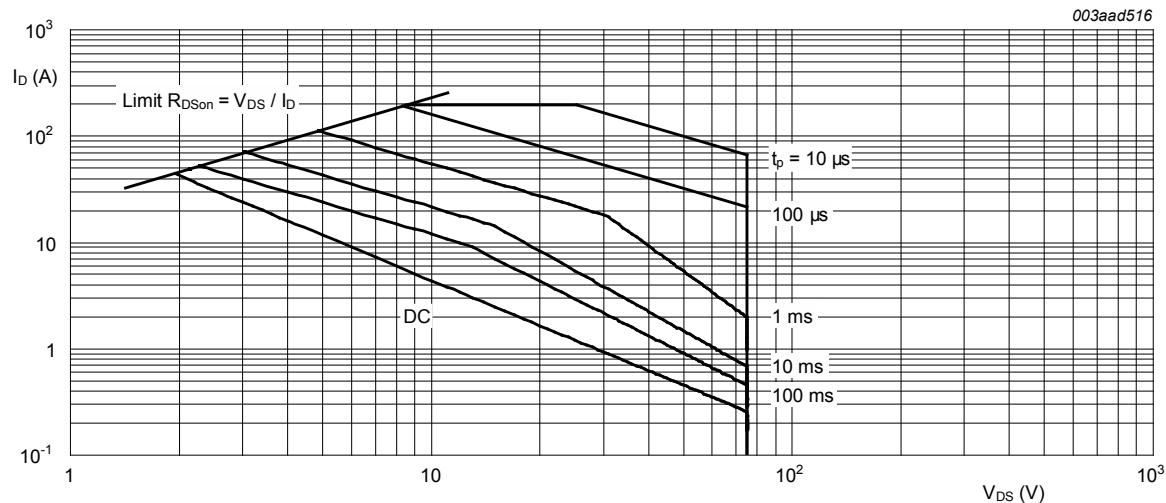


Fig. 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

$T_{mb} = 25^\circ\text{C}$; I_{DM} is single pulse

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 5		-	-	1.42	K/W

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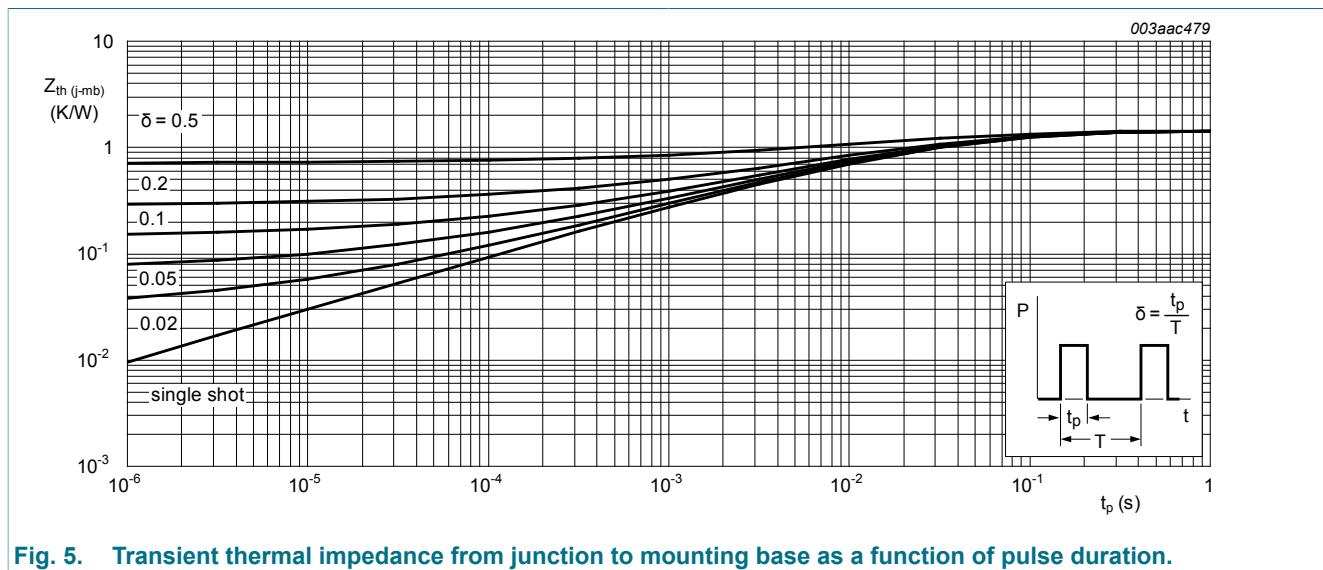


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration.

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu\text{A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$		75	-	-	V
		$I_D = 250 \mu\text{A}$; $V_{GS} = 0 \text{ V}$; $T_j = -55 \text{ }^\circ\text{C}$		68	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 10 ; Fig. 11		2	3	4	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ }^\circ\text{C}$; Fig. 10		-	-	4.4	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 175 \text{ }^\circ\text{C}$; Fig. 10		1	-	-	V
I_{DSS}	drain leakage current	$V_{DS} = 75 \text{ V}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$		-	0.02	1	μA
		$V_{DS} = 75 \text{ V}$; $V_{GS} = 0 \text{ V}$; $T_j = 175 \text{ }^\circ\text{C}$		-	-	500	μA
I_{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}$; $V_{DS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$		-	2	100	nA
		$V_{GS} = -20 \text{ V}$; $V_{DS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$		-	2	100	nA
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}$; $I_D = 20 \text{ A}$; $T_j = 175 \text{ }^\circ\text{C}$; Fig. 12 ; Fig. 13		-	-	43.2	$\text{m}\Omega$
		$V_{GS} = 10 \text{ V}$; $I_D = 20 \text{ A}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 12 ; Fig. 13		-	13.8	18	$\text{m}\Omega$
Dynamic characteristics							
$Q_{G(\text{tot})}$	total gate charge	$I_D = 20 \text{ A}$; $V_{DS} = 60 \text{ V}$; $V_{GS} = 10 \text{ V}$; Fig. 14		-	35	-	nC
Q_{GS}	gate-source charge			-	8.28	-	nC
Q_{GD}	gate-drain charge			-	14.24	-	nC

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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
C_{iss}	input capacitance	$V_{GS} = 0 \text{ V}$; $V_{DS} = 25 \text{ V}$; $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 15		-	1630	2173	pF
C_{oss}	output capacitance			-	274	329	pF
C_{rss}	reverse transfer capacitance			-	115	158	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 30 \text{ V}$; $R_L = 1.5 \Omega$; $V_{GS} = 10 \text{ V}$; $R_{G(ext)} = 10 \Omega$		-	18.5	-	ns
t_r	rise time			-	22.5	-	ns
$t_{d(off)}$	turn-off delay time			-	44.5	-	ns
t_f	fall time			-	19.8	-	ns

Source-drain diode

V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 25 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 16		-	0.85	1.2	V
t_{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A}/\mu\text{s}$; $V_{GS} = 0 \text{ V}$;		-	55.4	-	ns
Q_r	recovered charge	$V_{DS} = 30 \text{ V}$		-	143	-	nC

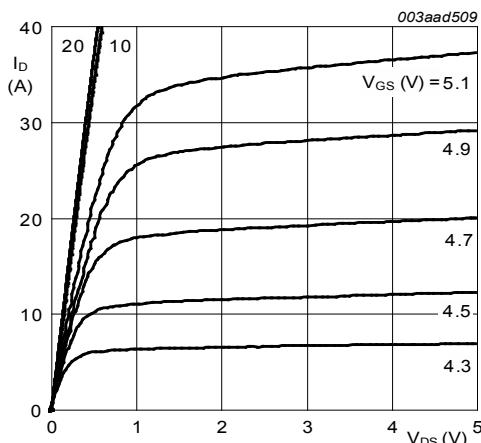


Fig. 6. Output characteristics: drain current as a function of drain-source voltage; typical values.

$T_j = 25 \text{ }^\circ\text{C}$

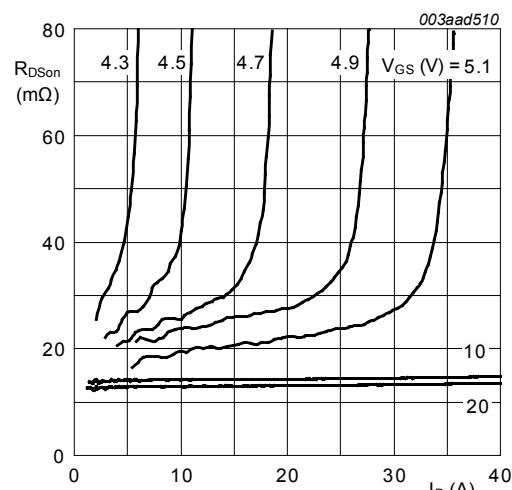


Fig. 7. Drain-source on-state resistance as a function of drain current; typical values.

$T_j = 25 \text{ }^\circ\text{C}$

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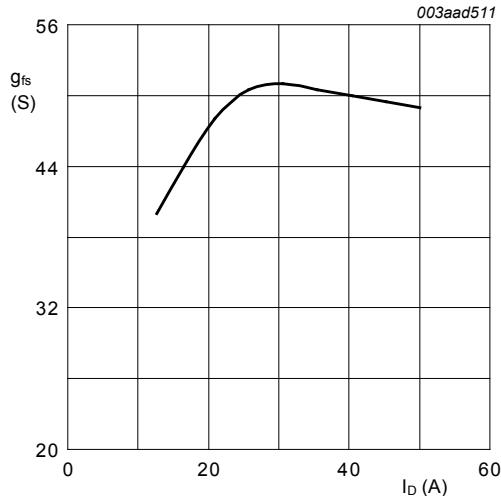


Fig. 8. Forward transconductance as a function of drain current; typical values.

$T_j = 25^\circ C; V_{DS} = 25V$

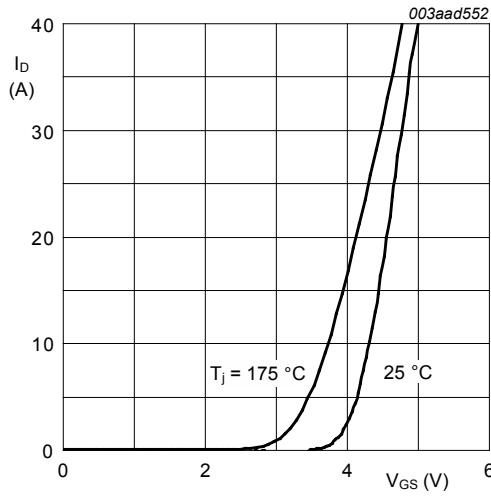


Fig. 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

$V_{DS} = 25V$

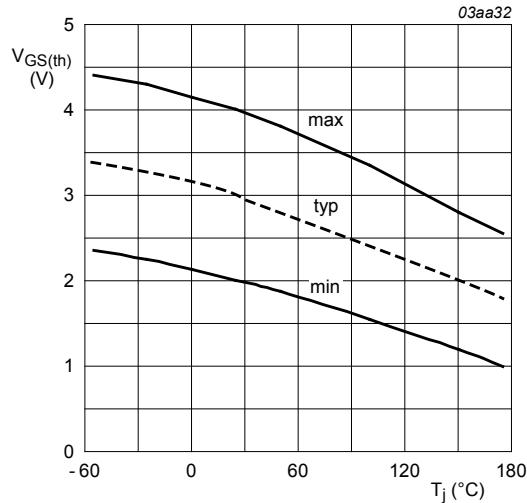


Fig. 10. Gate-source threshold voltage as a function of junction temperature

$I_D = 1mA; V_{DS} = V_{GS}$

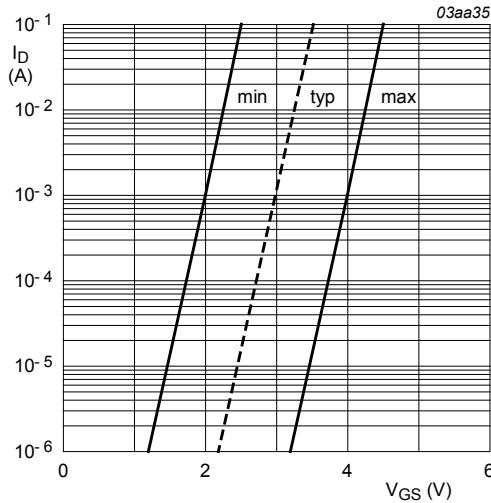


Fig. 11. Sub-threshold drain current as a function of gate-source voltage

$T_j = 25^\circ C; V_{DS} = 5V$

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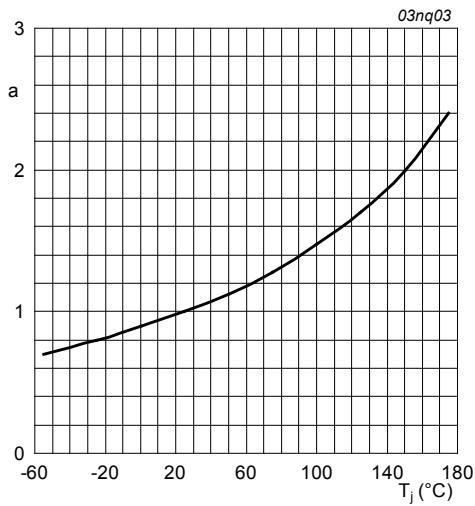


Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^\circ C)}}$$

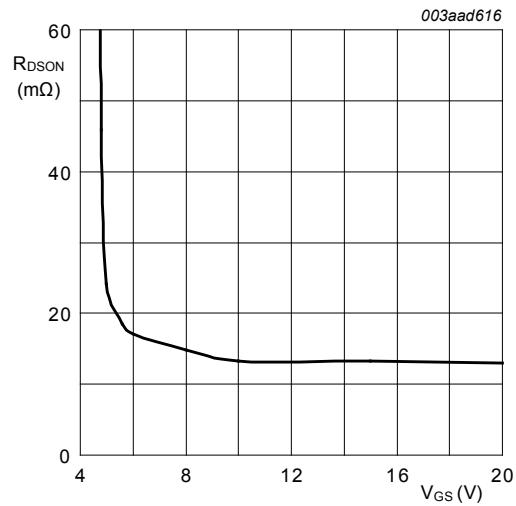


Fig. 13. Drain-source on-state resistance as a function of gate-source voltage; typical values.

$$T_j = 25^\circ C; I_D = 20A$$

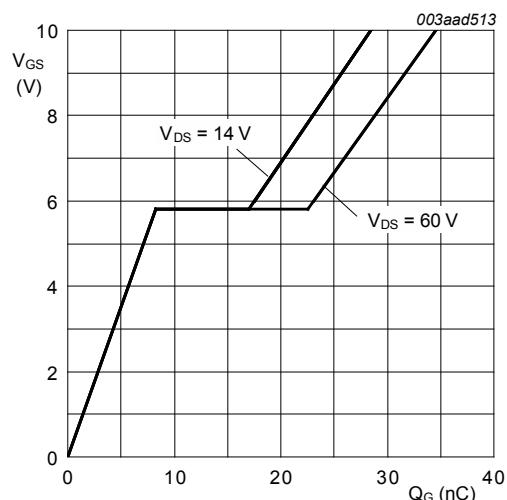


Fig. 14. Gate-source voltage as a function of gate charge; typical values.

$$T_j = 25^\circ C; I_D = 20A$$

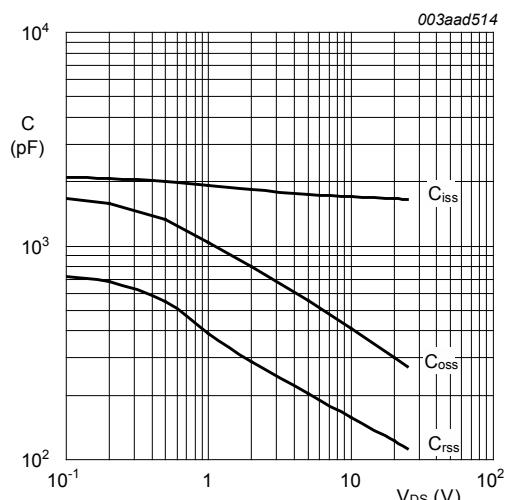
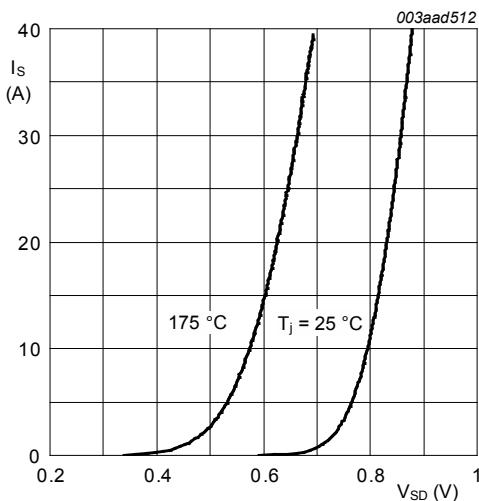


Fig. 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

$$V_{GS} = 0V; f = 1MHz$$

NXP Semiconductors**BUK7Y18-75B****N-channel TrenchMOS standard level FET****Fig. 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.**

$$V_{GS} = 0V$$

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11. Package outline

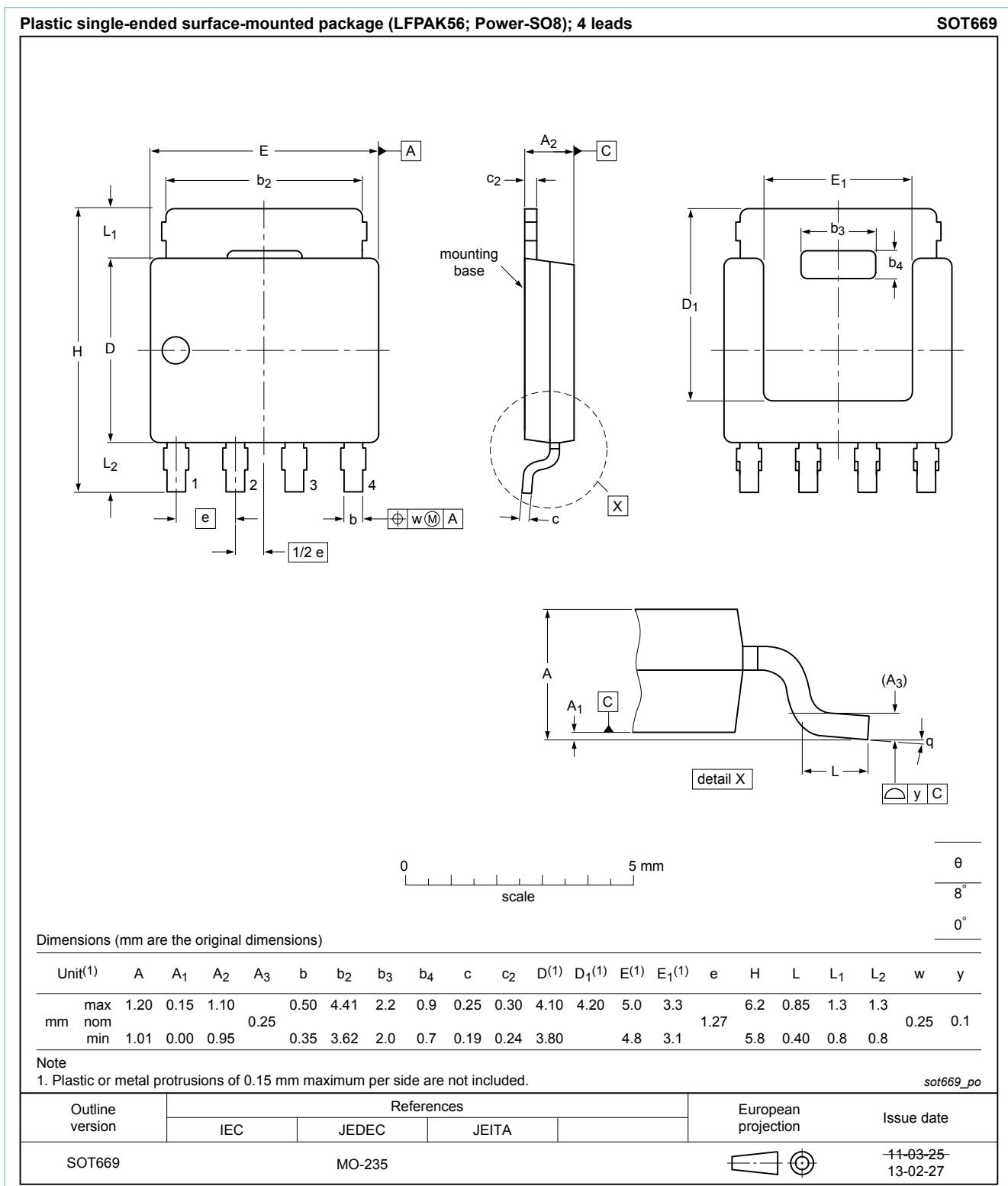


Fig. 17. Package outline LFPAK56; Power-SO8 (SOT669)

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12. Legal information

12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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